

Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 0050-1449-0		SERIAL NO. 087841-720	
LIST OF REFERENCES CITED BY APPLICANT				APPLICANT Takashi OHNO et al			
				FILING DATE October 1, 1997		GROUP 1756	
U.S. PATENT DOCUMENTS							
EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,011,723	04/30/94	Hargaya et al			
	AB	4,984,672	02/27/90	Tyan et al			
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
	AO	0 375 443	07/18/80	EUROPE			
	AP	0 195 332	08/24/85	EUROPE			
	AQ	0 405 010	01/02/91	EUROPE			
	AR	196 12 823	10/02/96	GERMANY			
	AS	0 373 955	08/20/90	EUROPE			
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)							
	AW	PATENT ABSTRACTS OF JAPAN, VOL. 13, NO. 180 (P.854), 27 APRIL 1989 (1989-04-27) & JP 01 010438 A (MATSUSHITA), 13 JANUARY 1989 (1989-01-13) "ABSTRACT"					
	AX	PATENT ABSTRACTS OF JAPAN, VOL. 1996, NO 9, 30 SEPTEMBER 1996 (1996-09-30) & JP 08 127176 A (HITACHI), 21 MAY 1996 (1996-05-21) "ABSTRACT"					
	AY						
	AZ						
Examiner					Date Considered		

*Examiner: Initial if reference is considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

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ATTY. DOCKET NO.

0050-1449-0

SERIAL NO.

08/941,720

APPLICANT

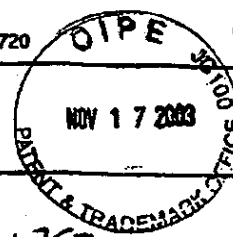
Takashi OHNO, et al.

FILING DATE

October 1, 1997

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LIST OF REFERENCES CITED BY APPLICANT
(Use Several Sheets if Necessary)

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,011,723	04/25/91	MAKOTO HARTGATA, et al.	430	945	
	AB	4,904,577	02/27/90	Yuan-Sheng TYAN, et al.	430	945	
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO
	AL	0-378-443	07/16/90	EUROPE	XXX
	AM	0-195-532	09/14/86	EUROPE	XXX
	AN	0-405-618	01/02/91	EUROPE	XXX
	AO				
	AP				

OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, Etc.)

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EXAMINER

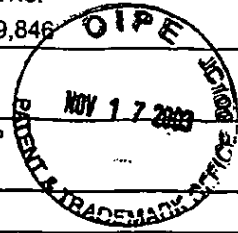
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Form PTO 1449
(Modified)U.S. DEPARTMENT OF COMMERCE
PATENT AND TRADEMARK OFFICEATTY DOCKET NO.
210159US0CONTSERIAL NO.
09/919,846

LIST OF REFERENCES CITED BY APPLICANT

APPLICANT
Takashi OHNO, et al.FILING DATE
August 2, 2001GROUP
1756

U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA						
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FOREIGN PATENT DOCUMENTS

		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION	
					YES	NO
<i>1</i>	AO	JP-A-6-195747	07/15/1994	JAPAN (w/English-language Abstract)		
<i>2</i>	AP	JP-A-6-12674	01/21/1994	JAPAN (w/English-language Abstract)		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

	AW	
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	AZ	<input type="checkbox"/> Additional References sheet(s) attached

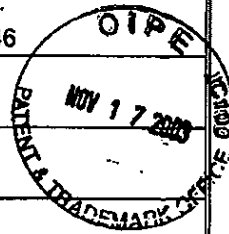
Examiner

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U.S. PATENT DOCUMENTS

EXAMINER INITIAL		DOCUMENT NUMBER	DATE	NAME	CLASS	SUB CLASS	FILING DATE IF APPROPRIATE
	AA	5,011,723	04/30/1991	M. HIRIGAYA			
	AB						
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					YES	NO
	AO	JP 01 010438 A	01/12/1989	JAPAN (w/ Abstract)		
	AP	DE 196 12 823 A	10/02/1996	GERMANY		
	AQ	JP 08 127176 A	05/21/1996	JAPAN (w/ Abstract)		
	AR	EP 0 373 955 A	06/20/1990	EUROPE		
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OTHER REFERENCES (Including Author, Title, Date, Pertinent Pages, etc.)

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☐ Additional References sheet(s) attached

Examiner

Date Considered

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02/10/01*



Form PTO 1449 (Modified)		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE		ATTY DOCKET NO. 210159US0CONT		SERIAL NO. 09/919,846	
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FOREIGN PATENT DOCUMENTS							
		DOCUMENT NUMBER	DATE	COUNTRY	TRANSLATION YES NO		
<i>he</i>	AO	JP 8-180414	07/12/1996	JAPAN (w/English Abstract)			
<i>he</i>	AP	JP 8-216522	08/27/1996	JAPAN (w/English Abstract)			
<i>he</i>	AQ	JP 8-249721	09/27/1996	JAPAN (w/English Abstract)			
<i>he</i>	AR	JP 8-7343	01/12/1996	JAPAN (w/English Abstract)			
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Examiner has reviewed the references cited by applicant and has determined that they are pertinent to the invention and are being cited in conformance and not considered. Include copy of this form with next communication to applicant.